

**Notice of References Cited**

Application/Control No.

10/067,580

Applicant(s)/Patent Under

Reexamination

ANDREW ET AL.

Examiner

Alicia Baturay

Art Unit

2155

Page 1 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,757,821 B1	06-2004	Akiyama et al.	713/100
*	B	US-6,233,448 B1	05-2001	Alperovich et al.	455/417
*	C	US-6,256,635 B1	07-2001	Arrouye et al.	707/102
*	D	US-2004/0210649 A1	10-2004	Bhagal et al.	709/222
*	E	US-6,269,395 B1	07-2001	Blatherwick et al.	709/219
*	F	US-6,449,642 B2	09-2002	Bourke-Dunphy et al.	709/222
*	G	US-6,636,961 B1	10-2003	Braun et al.	713/1
*	H	US-6,301,707 B1	10-2001	Carroll et al.	717/177
*	I	US-6,496,979 B1	12-2002	Chen et al.	717/178
*	J	US-2005/0060532 A1	03-2005	Dorenbosch et al.	713/100
*	K	US-6,424,840 B1	07-2002	Fitch et al.	455/456.1
*	L	US-6,272,545 B1	08-2001	Flanagin et al.	709/228
*	M	US-2003/0167405 A1	09-2003	Freund et al.	713/201

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/067,580		Applicant(s)/Patent Under Reexamination ANDREW ET AL.	
	Examiner Alicia Baturay		Art Unit 2155	Page 2 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,370,646 B1	04-2002	Goodman et al.	713/100
*	B	US-2002/0075844 A1	06-2002	Hagen, W. Alexander	370/351
*	C	US-6,512,467 B1	01-2003	Hanko et al.	341/22
*	D	US-6,760,046 B2	07-2004	I'Anson et al.	715/746
*	E	US-6,920,491 B2	07-2005	Kim, Hyon T.	709/220
*	F	US-6,769,008 B1	07-2004	Kumar et al.	709/201
*	G	US-6,542,515 B1	04-2003	Kumar et al.	370/463
*	H	US-6,029,196 A	02-2000	Lenz, Michael A.	709/221
*	I	US-6,345,319 B1	02-2002	Lin et al.	710/8
*	J	US-6,542,515 B1	04-2003	Kumar et al.	370/463
*	K	US-6,029,196 A	02-2000	Lenz, Michael A.	709/221
*	L	US-6,345,319 B1	02-2002	Lin et al.	710/8
*	M	US-5,748,980 A	05-1998	Lipe et al.	710/8

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/067,580		Applicant(s)/Patent Under Reexamination ANDREW ET AL.	
	Examiner Alicia Baturay		Art Unit 2155	Page 3 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0032754 A1	03-2002	Logston et al.	709/219
*	B	US-2002/0073210 A1	06-2002	Low et al.	709/228
*	C	US-6,963,908 B1	11-2005	Lynch et al.	709/220
*	D	US-2003/0159028 A1	08-2003	Mackin et al.	713/100
*	E	US-5,784,563 A	07-1998	Marshall et al.	709/221
*	F	US-6,795,846 B1	09-2004	Merriam, Charles	709/203
*	G	US-6,826,581 B2	11-2004	Moslander et al.	707/203
*	H	US-5,555,416 A	09-1996	Owens et al.	717/178
*	I	US-6,750,883 B1	06-2004	Parupudi et al.	715/763
*	J	US-6,748,195 B1	06-2004	Phillips, W. Garland	455/41.2
*	K	US-6,680,919 B1	01-2004	Rauhala, Kristian	370/310
*	L	US-6,611,862 B2	08-2003	Reisman, Richard R.	709/217
*	M	US-6,922,723 B1	07-2005	Sharp et al.	709/221

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/067,580	Applicant(s)/Patent Under Reexamination ANDREW ET AL.	
	Examiner Alicia Baturay	Art Unit 2155	Page 4 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,925,492 B2	08-2005	Shirriff, Kenneth W.	709/220
*	B	US-6,493,751 B1	12-2002	Tate et al.	709/221
*	C	US-2003/0026220 A1	02-2003	Uhlik et al.	370/328
*	D	US-2003/0028649 A1	02-2003	Uhlik et al.	709/228
*	E	US-6,594,695 B1	07-2003	Vasamsetti et al.	709/220
*	F	US-6,961,762 B1	11-2005	Yeap et al.	709/221
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.